








Test Equipment	Ordering Information	Pictures	Description
<p>4/3 POINT UNIVERSAL PROBE for 4 point and spreading resistance measurements with standard co-ordinate table fitted with steel hinged cover to screen from electrical interference and light shield painted semi-gloss black 通用型四點探針 通用型三點探針 (SRP)</p>	<p>Probe spacing 1.00mm is fitted as standard. 1.27mm (50 mils) and 1.590 (62.6 mils) are available. Needle material is normally Tungsten Carbide, Osmium alloy tips can be supplied. Needle tip radius 25μ</p>		<p>Highly repeatable needle contact conditions.</p> <p>Individually adjustable needle loadings with direct indication of set load.</p> <p>Micrometer controlled slice displacement.</p> <p>4-point measurement of wafer resistivity and 3-point spreading resistance measurements.</p> <p>Hinged steel cover to eliminate effects of light and electrical interference.</p>
<p>MULTIPOSITION WAFER PROBE Comprising cylindrical probe head, mounting, multiposition table. Available in both 6" and 8" versions 多位置點量測四點探針</p>	<p>Probe head characteristics 6" or 8" version</p>		<p>8" and 6" versions available.</p> <p>Lever operated probe with switched current leads to prevent sparking.</p> <p>Repositioning accuracy within 1mm.</p> <p>Precision low maintenance slides.</p> <p>Shrouded measuring area to minimize light and electrical interference.</p>
<p>MULTIHEIGHT PROBE Comprising cylindrical probe head, flat base with column and raising and lowering mechanism. 可調高度量測四點探針</p>	<p>Probe head characteristics</p>		<p>Height adjustable to cope with samples from thin layers to ingots.</p> <p>Lever operated probe with switched current leads to prevent sparking.</p> <p>Measures samples up to 10" deep.</p> <p>Width of sample limited only by need to support ends.</p>
<p>HAND APPLIED PROBE Comprising mounting with cylindrical probe head and lead for large substrates and ingots. 手壓式四點探針</p>	<p>Probe head characteristics</p>		<p>Insulating PTFE body.</p> <p>4-point cylindrical probe head is easily changed.</p> <p>Shorting switch to prevent sparking.</p> <p>Easy placement by hand.</p> <p>Measurement of large samples unable to fit on standard test equipment.</p>
<p>MICROPOSITION PROBE Comprising X-Y coordinate stage and column with raising and lowering mechanism 小樣品微調量測位置四點探針</p>	<p>Probe head characteristics</p>		<p>X-Y Micro-manipulation of small samples.</p> <p>3" diameter sample capacity.</p> <p>Sample can be retained by vacuum.</p> <p>Lever operated probe with switched current leads to prevent sparking.</p>
<p>RESISTIVITY TEST UNIT – RM3 - CONSTANT CURRENT SOURCE and VOLTMETER 10nA – 100mA 四點探針用電壓電流源</p>	<p>Operating voltage</p>		<p>The new Jandel RM3 has a smaller footprint, a wider current range, a wider voltage range, and has RS232 and USB connectivity. (As compared to the RM2).</p> <p>Readings can be displayed as voltage or alternatively direct readings in Ohms/square are available.</p>
<p>RESISTIVITY TEST UNIT – HM20 -CONSTANT CURRENT SOURCE and VOLTMETER 100nA – 10mA 掌上式四點探針用電壓電流源</p>			<p>The new Jandel HM20 portable meter is now available.</p> <p>There are 6 set currents from 100nA up to 10mA and readings can be displayed in mV or in Ohms/square.</p> <p>The unit is chargeable via a power adaptor or via USB giving long battery life for easy portability.</p>

Spares 備品

<p>SPARE 4-POINT GUIDANCE UNIT For Universal Probe complete with four needles.</p>	<p>Needle Material and Spacing</p>		
<p>SPARE NEEDLES – SET OF FOUR For Universal Probe, solid Tungsten Carbide, 0.5mm diameter, 45° included angle, complete with ligaments ready to fit.</p>	<p>Needle Specifications.</p>		
<p>SPAREE NEEDLES – SET OF FOUR As above but with 50% Osmium alloy tips.</p>	<p>Needle Specifications</p>		

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